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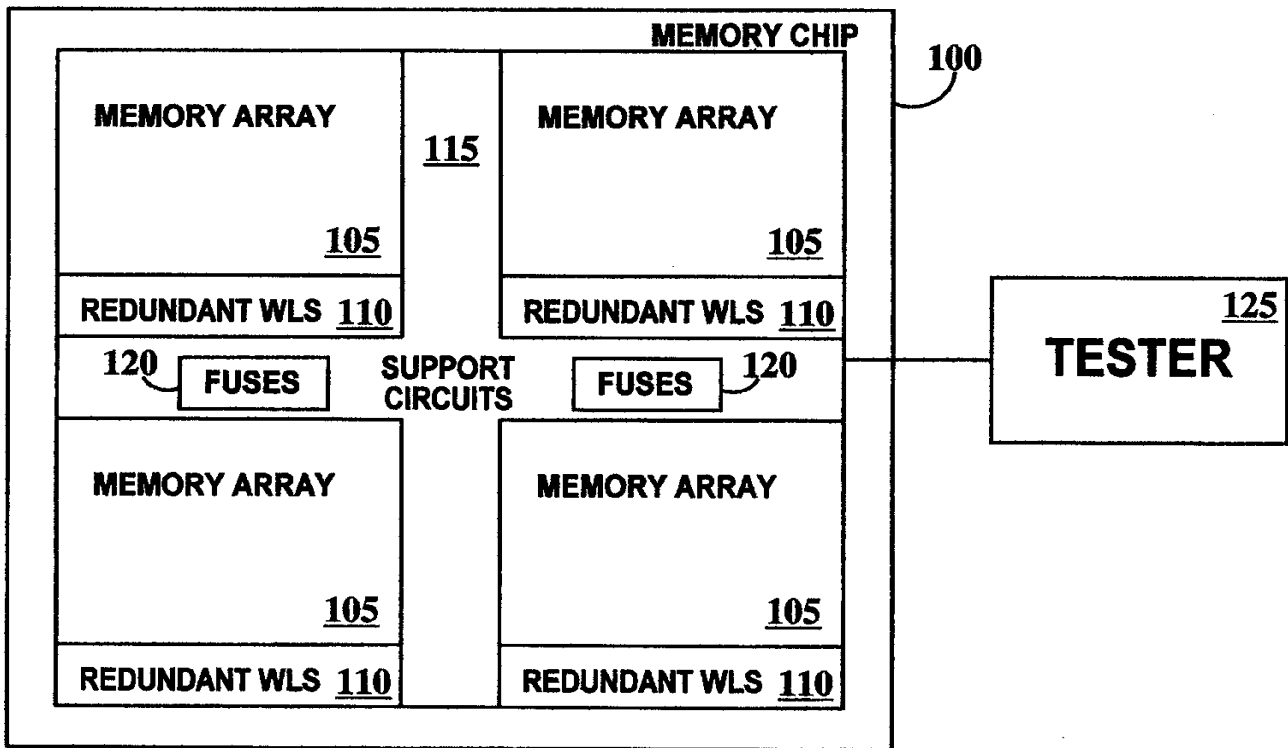


FIG. 1

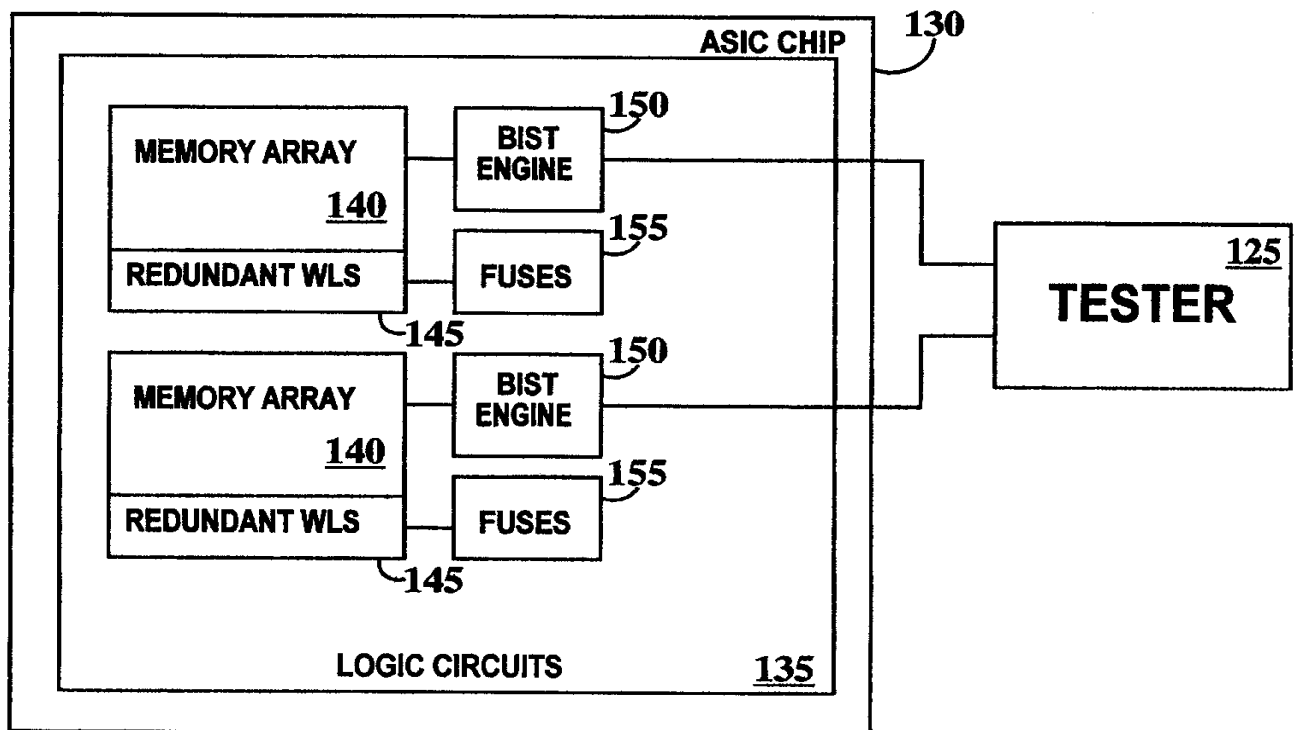


FIG. 2

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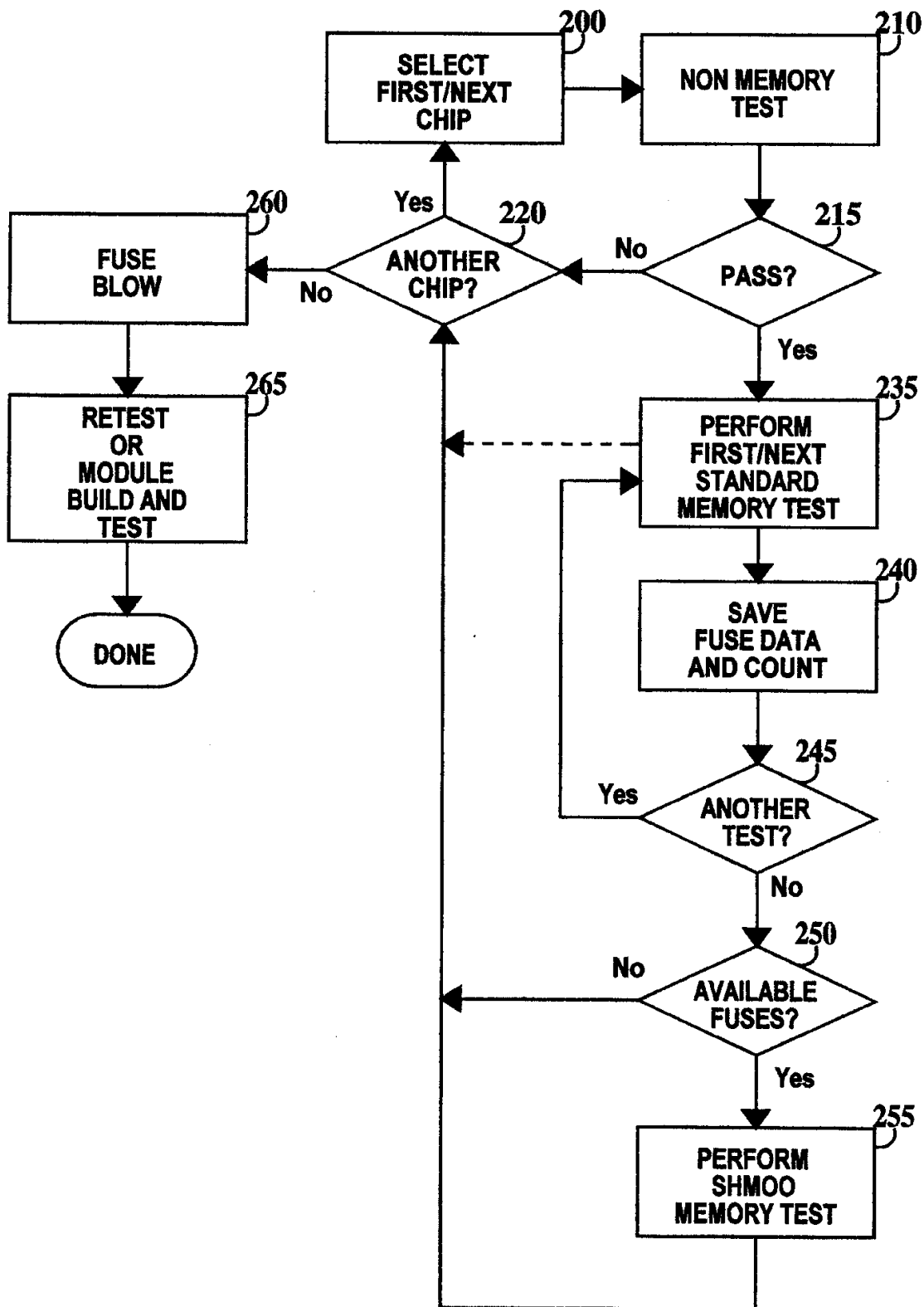


FIG. 3

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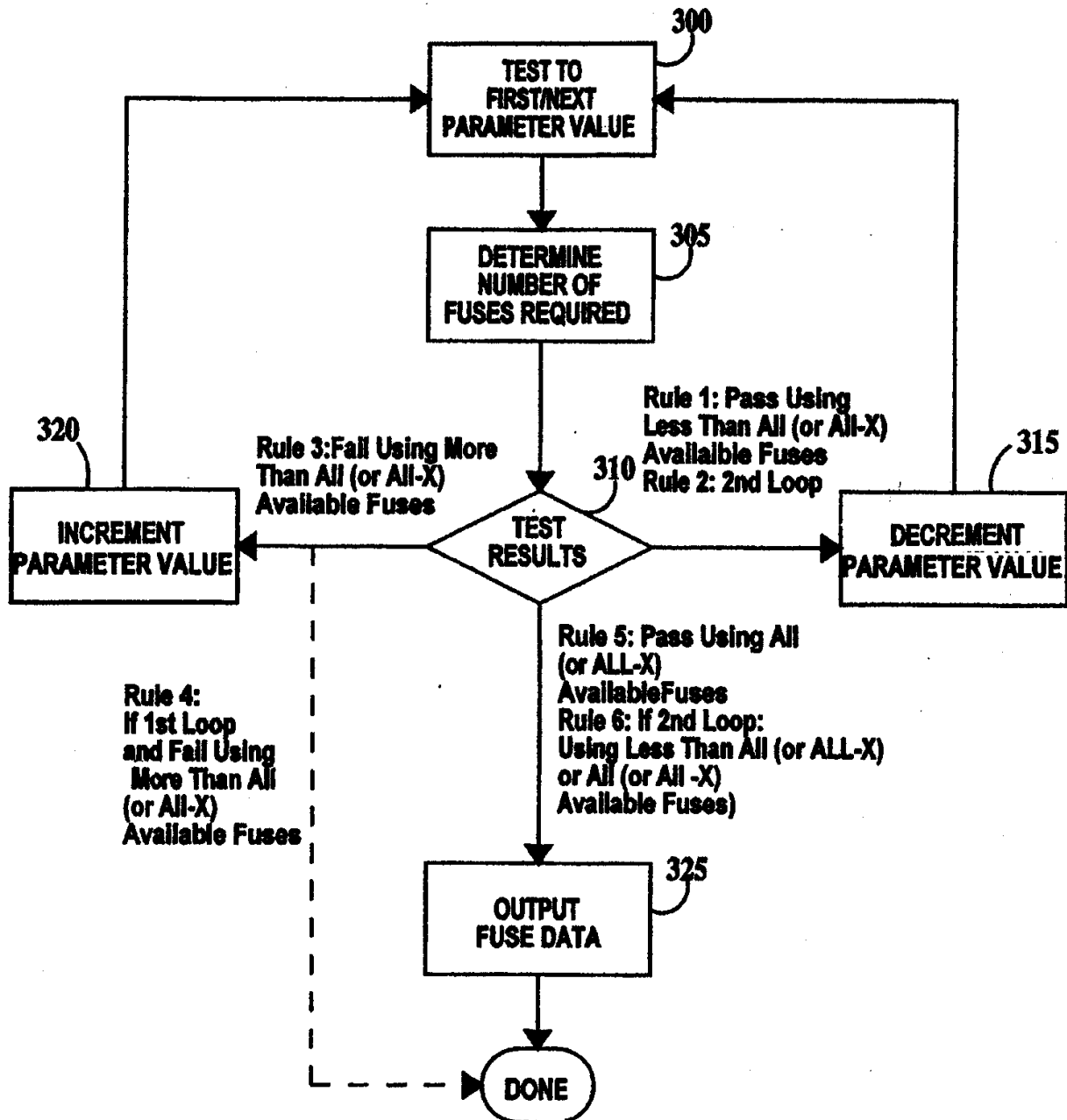
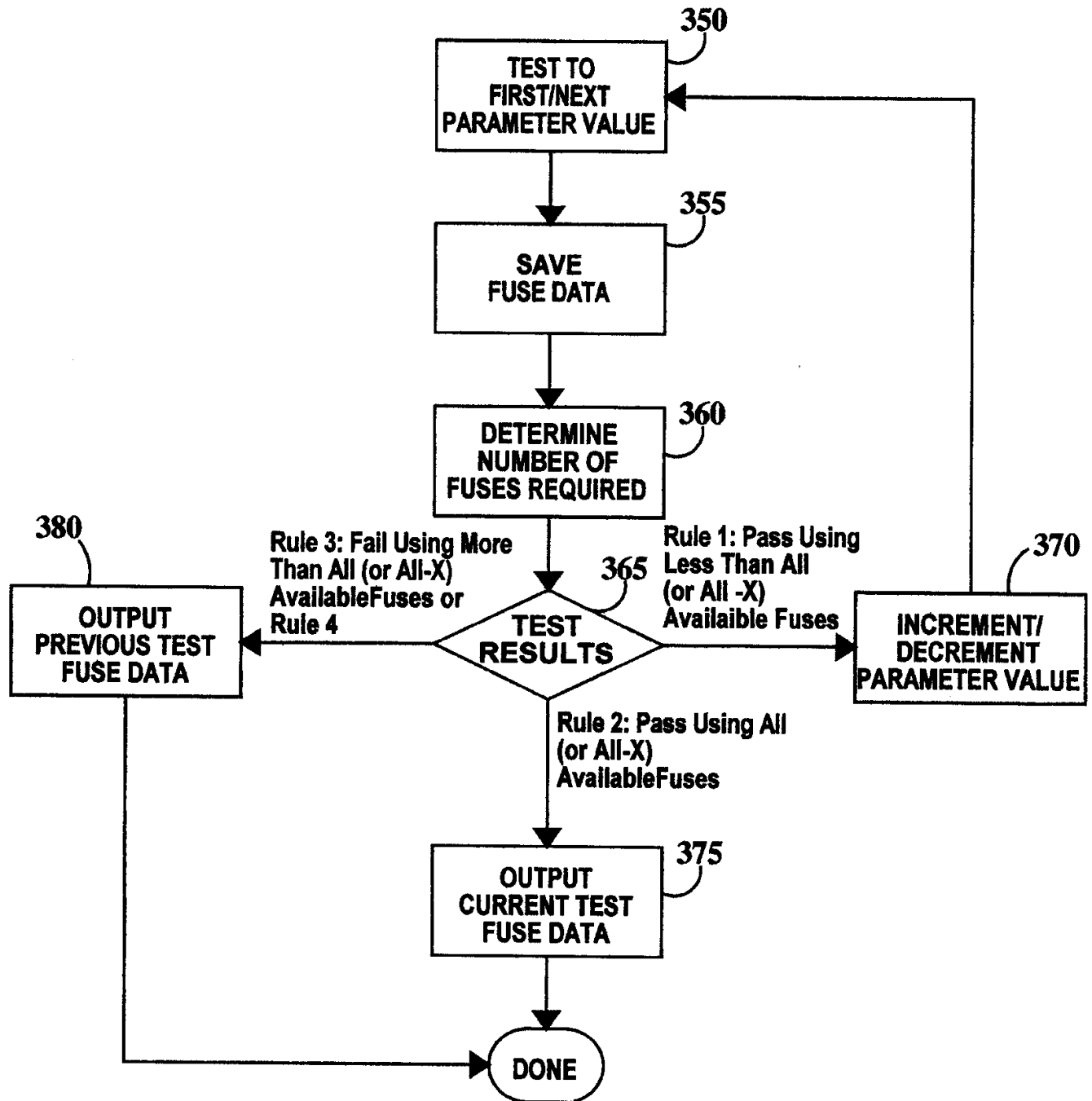


FIG. 4

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**FIG. 5**

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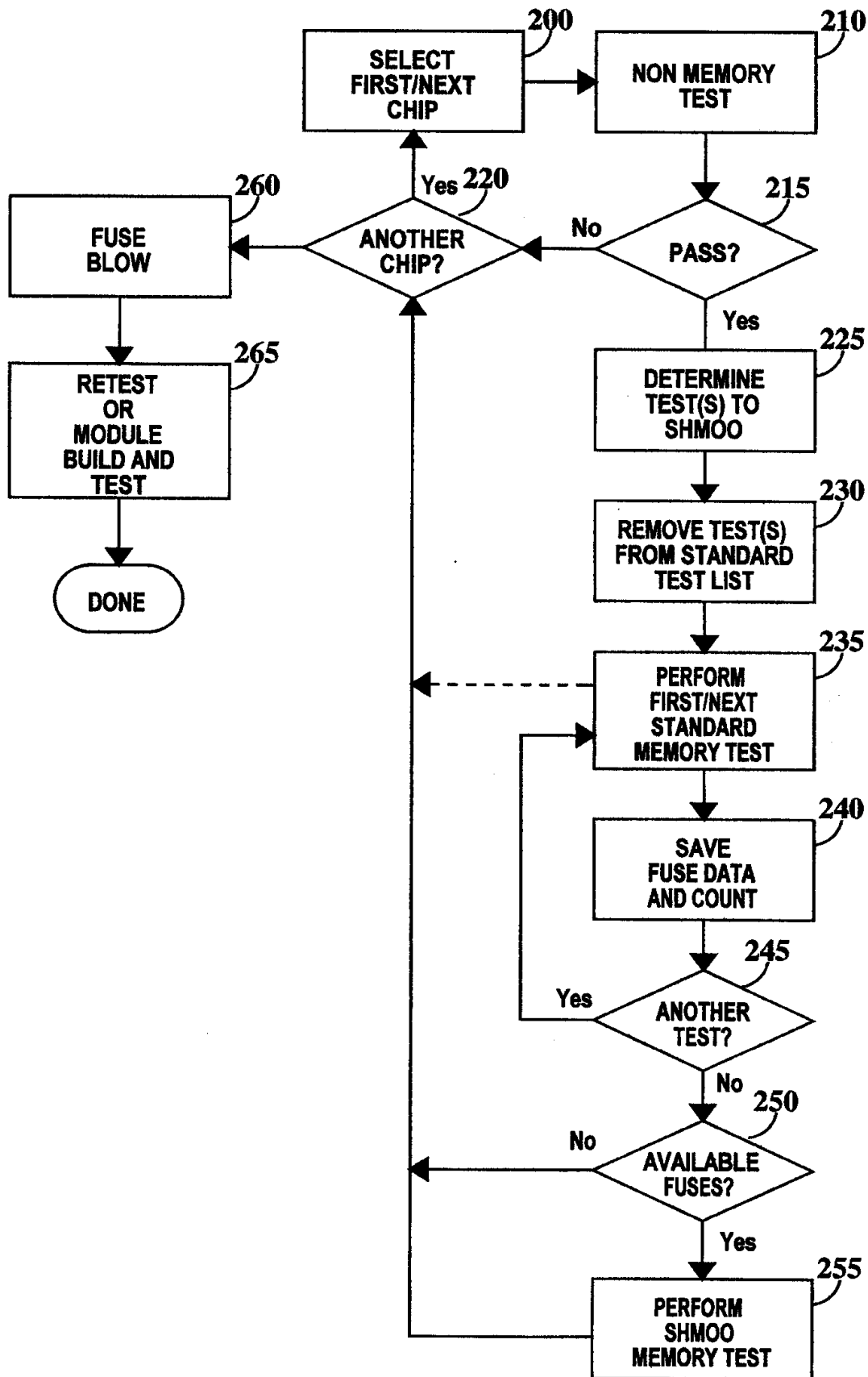


FIG. 6

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TEST SEQ.	TEST VOLTAGE	TEST RESULTS AND FUSING ACTION
1	V1 = FIRST SHMOO LIMIT	PASS with (M-L)>0 then goto V2, with (M-L)=0 then fuse at V1 FAIL with (M-L) = or > 0 then done
2	V2 = SECOND SHMOO LIMIT	PASS with (M-L)>0 or (M-L)=0 then fuse at V1 FAIL with (M-L)<0 then goto V3
3	$V3 = (V1 + V2)/2$	PASS with (M-L)>0 then goto V4, with (M-L)=0 then fuse at V3 FAIL with (M-L)<0 then goto V4'
4	$V4 = (V2 + V3)/2$	PASS with (M-L)>0 then goto V5, with (M-L)=0 then fuse at V4 FAIL with (M-L)<0 then goto V5'
5	$V4' = (V1 + V3)/2$	PASS with (M-L)>0 then goto V5'', with (M-L)=0 then fuse at V4' FAIL with (M-L)<0 then goto V5'''
6	$V5 = (V2 + V4)/2$	PASS with (M-L)>0 then goto V6, with (M-L)=0 then fuse at V5 FAIL with (M-L)<0 then goto V6'

FIG. 7A

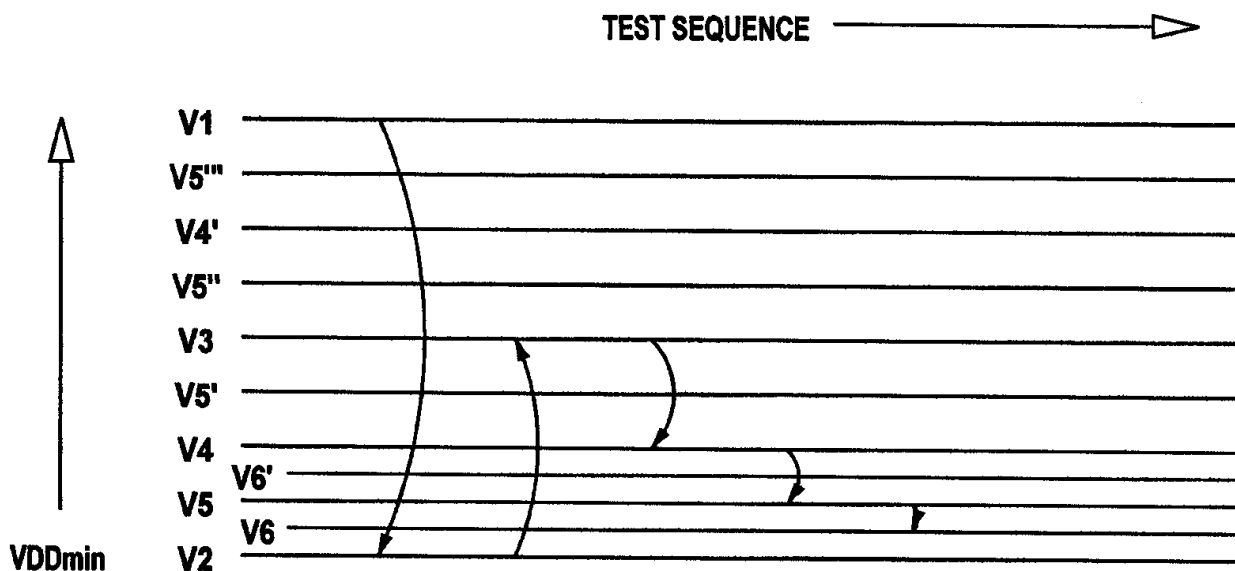


FIG. 7B

NUMBER OF CHIPS GOOD AT AS A FUNCTION OF TEST VOLTAGE

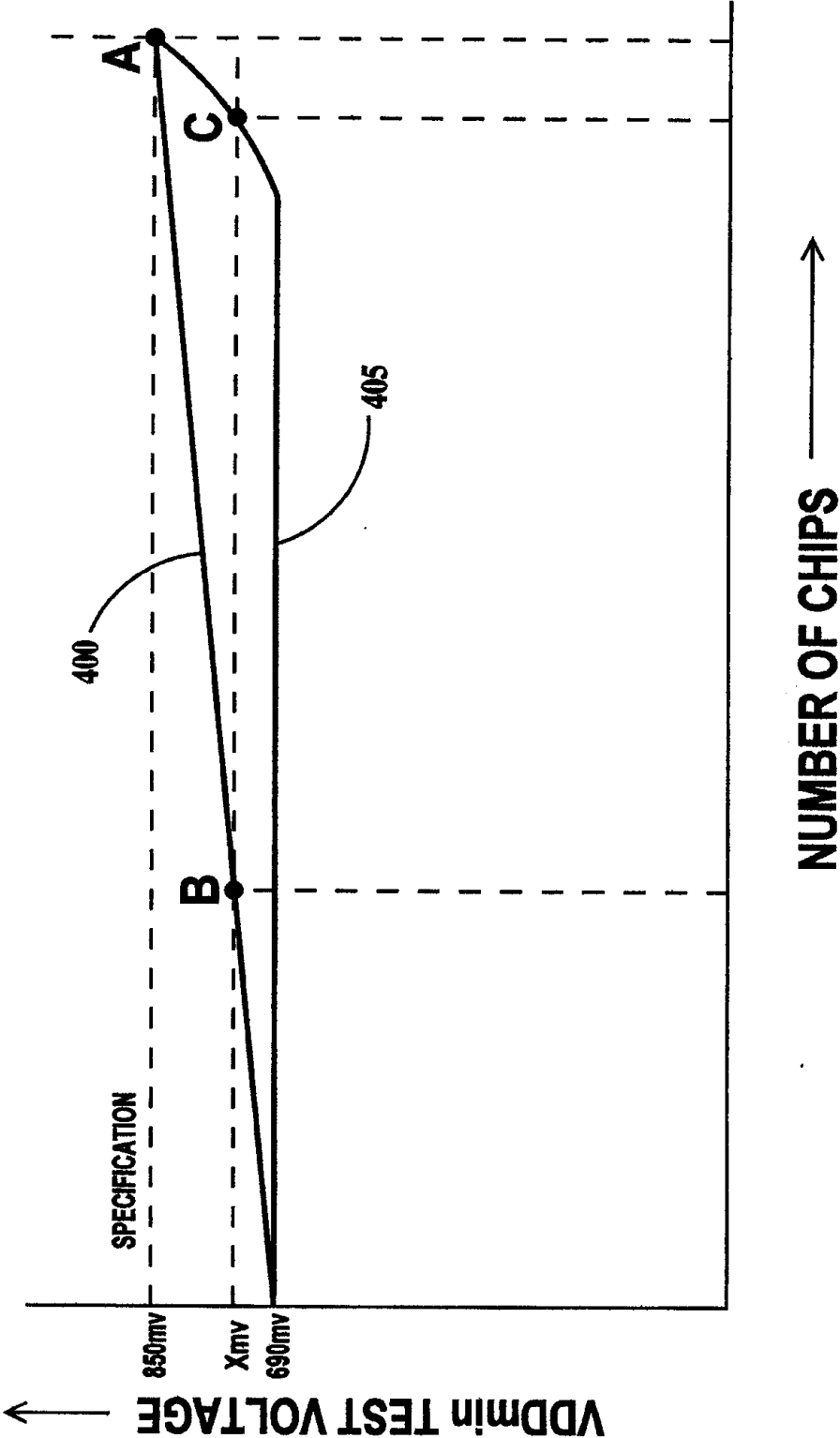


FIG. 8